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TITLE: WAFER LEVEL CSP, 120 I/O, 5.29 X 5.28 PKG, 0.4 MM PITCH	DOCUMENT NO: 98ASA00311D	REV: A
	STANDARD: NON-JEDEC	
	SOT1774-1	07 JAN 2016



NOTES:

1. ALL DIMENSIONS IN MILLIMETERS.

2. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.

3. MAXIMUM SOLDER BALL DIAMETER MEASURED PARALLEL TO DATUM C.

4. DATUM C, THE SEATING PLANE, IS DETERMINED BY THE SPHERICAL CROWNS OF THE SOLDER BALLS.

5. PARALLELISM MEASUREMENT SHALL EXCLUDE ANY EFFECT OF MARK ON TOP SURFACE OF PACKAGE.

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